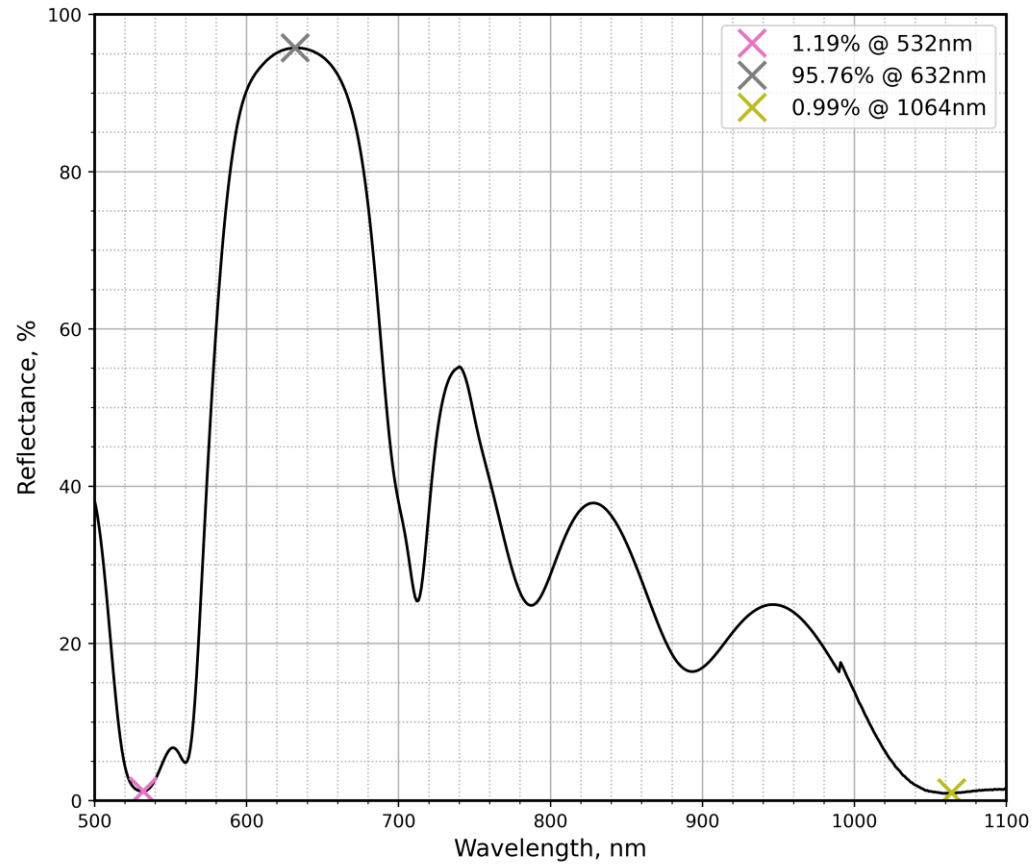


S1 (arrow marks): HRa > 95% @ 632 nm + Ra < 3% @ 532 + Ra < 2% @ 1064 + 2940 nm, AOI 45°  
S2: ARa < 2% @ 532 nm + ARa < 2% @ 1064 nm + ARa < 2% @ 2940 nm, AOI 45°



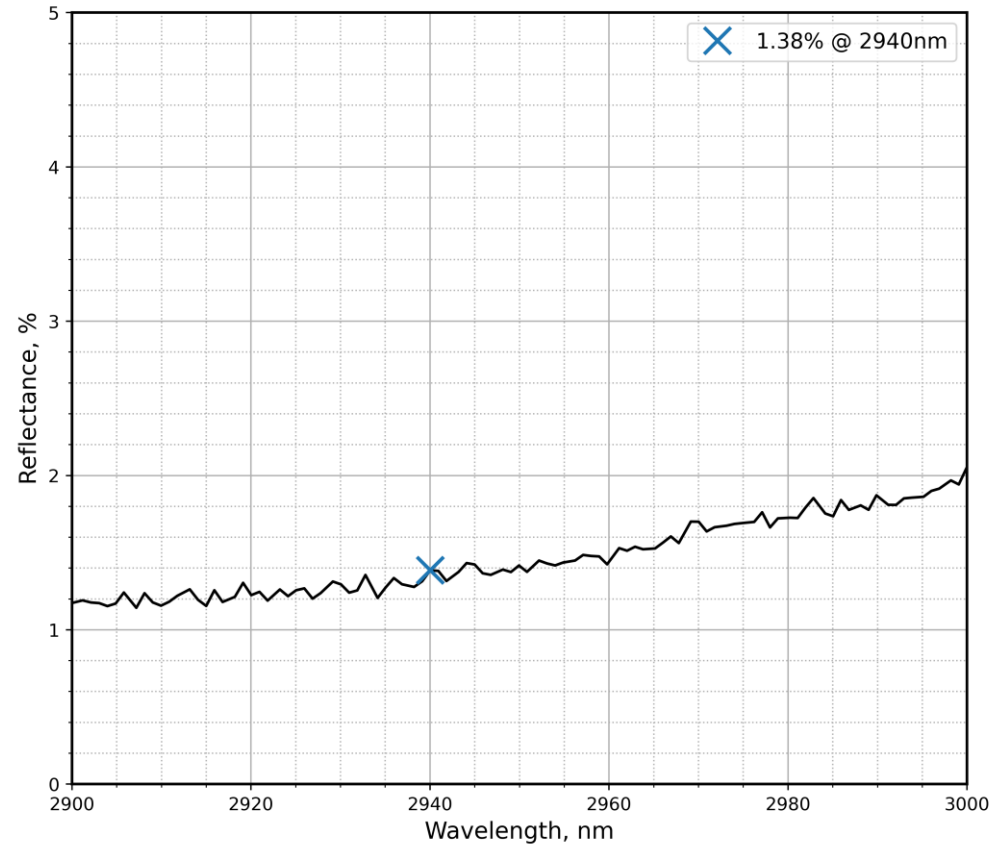
PO4154 Ra i45

Fig. 1.

SIDE MEASURED: S1+S2 (good component)

COMMENTS: Margin of measurement error: +/-0.25%

S1 (arrow marks): HRa > 95% @ 632 nm + Ra < 3% @ 532 + Ra < 2% @ 1064 + 2940 nm, AOI 45°  
S2: ARa < 2% @ 532 nm + ARa < 2% @ 1064 nm + ARa < 2% @ 2940 nm, AOI 45°



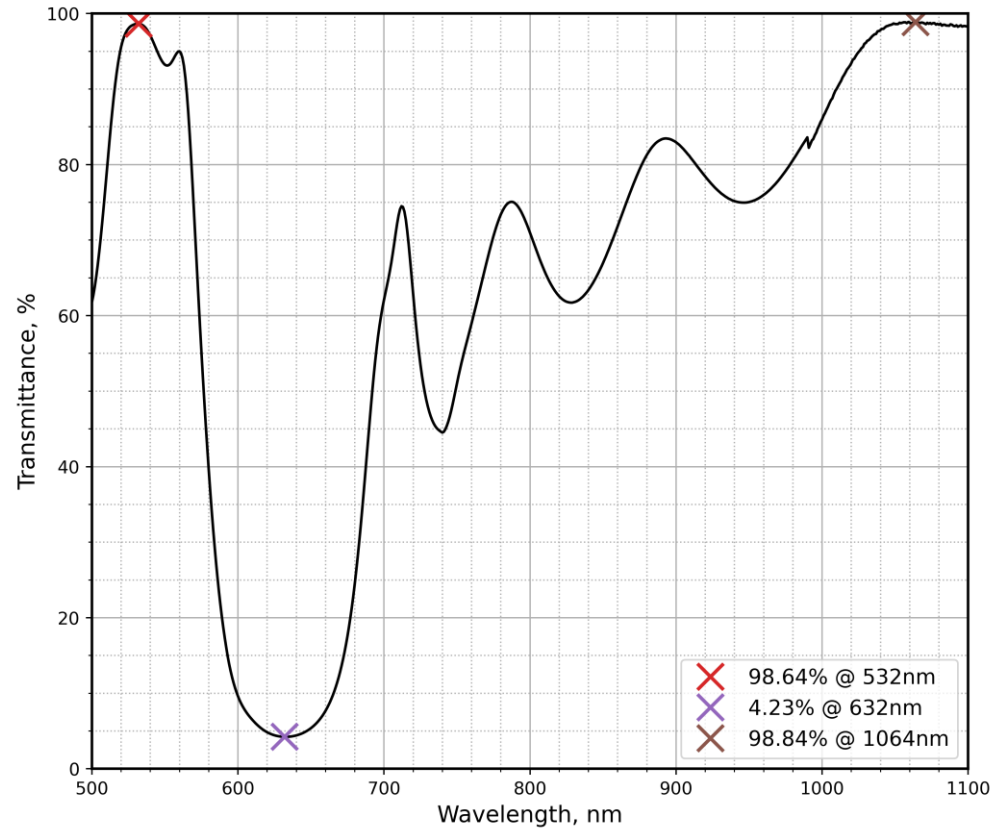
PO4154 Ra i45

Fig. 2.

SIDE MEASURED: S1+S2 (good component)

COMMENTS: Margin of measurement error: +/-0.25%

S1 (arrow marks):  $H_{Ra} > 95\%$  @ 632 nm +  $R_a < 3\%$  @ 532 +  $R_a < 2\%$  @ 1064 + 2940 nm, AOI 45°  
 S2:  $AR_a < 2\%$  @ 532 nm +  $AR_a < 2\%$  @ 1064 nm +  $AR_a < 2\%$  @ 2940 nm, AOI 45°



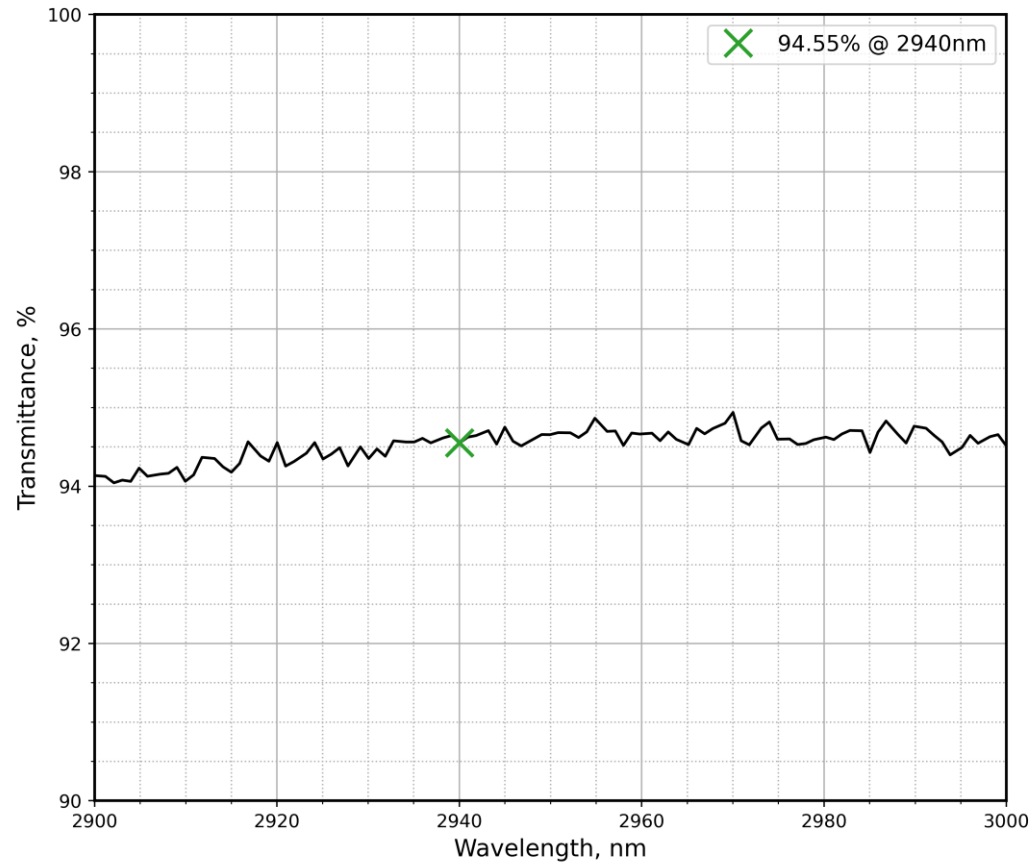
PO4154 Ta i45

Fig. 3.

SIDE MEASURED: S1+S2 (good component)

COMMENTS: Margin of measurement error: +/-0.25%

S1 (arrow marks): HRa > 95% @ 632 nm + Ra < 3% @ 532 + Ra < 2% @ 1064 + 2940 nm, AOI 45°  
S2: ARa < 2% @ 532 nm + ARa < 2% @ 1064 nm + ARa < 2% @ 2940 nm, AOI 45°



PO4154 Ta i45

Fig. 4.

SIDE MEASURED: S1+S2 (good component)

COMMENTS: Margin of measurement error: +/-0.25%